

Product data sheet

1. Product profile

1.1 General description

NPN silicon RF transistor for high speed, low noise applications in a plastic, 4-pin dual-emitter SOT143B package.

The BFU520 is part of the BFU5 family of transistors, suitable for small signal to medium power applications up to 2 GHz.

1.2 Features and benefits

- Low noise, high breakdown RF transistor
- AEC-Q101 qualified
- Minimum noise figure (NF_{min}) = 0.65 dB at 900 MHz
- Maximum stable gain 20 dB at 900 MHz
- 11 GHz f_T silicon technology

1.3 Applications

- Applications requiring high supply voltages and high breakdown voltages
- Broadband amplifiers up to 2 GHz
- Low noise amplifiers for ISM applications
- ISM band oscillators

1.4 Quick reference data

Table 1. Quick reference data

T_{amb} = 25 °C unless otherwise specified

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{CB}	collector-base voltage	open emitter		-	-	24	V
V_{CE}	collector-emitter voltage	open base		-	-	12	V
		shorted base		-	-	24	V
V_{EB}	emitter-base voltage	open collector		-	-	2	V
I _C	collector current			-	5	30	mA
P _{tot}	total power dissipation	T _{sp} ≤ 87 °C	<u>[1]</u>	-	-	450	mW
h _{FE}	DC current gain	$I_C = 5 \text{ mA}; V_{CE} = 8 \text{ V}$		60	95	200	
C _c	collector capacitance	$V_{CB} = 8 \text{ V}; f = 1 \text{ MHz}$		-	0.52	-	pF
f _T	transition frequency	$I_C = 10 \text{ mA}; V_{CE} = 8 \text{ V}; f = 900 \text{ MHz}$		-	10.5	-	GHz



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Table 1. Quick reference data ...continued

T_{amb} = 25 °C unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
G _{p(max)}	maximum power gain	$I_C = 5 \text{ mA}; V_{CE} = 8 \text{ V}; f = 900 \text{ MHz}$	-	20	-	dB
NF_{min}	minimum noise figure	I_C = 1 mA; V_{CE} = 8 V; f = 900 MHz; Γ_S = Γ_{opt}	-	0.65	-	dB
P _{L(1dB)}	output power at 1 dB gain compression	I_C = 10 mA; V_{CE} = 8 V; Z_S = Z_L = 50 Ω ; f = 900 MHz	-	6.5	-	dBm

- [1] T_{sp} is the temperature at the solder point of the collector lead.
- [2] If K > 1 then $G_{p(max)}$ is the maximum power gain. If K < 1 then $G_{p(max)} = MSG$.

2. Pinning information

Table 2. Discrete pinning

Pin	Description	Simplified outline	Graphic symbol
1	collector		,
2	base		
3	emitter		2—
4	emitter		3, 4
		1 2	aaa-010459

3. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	me Description				
BFU520	-	plastic surface-mounted package; 4 leads	SOT143B			
OM7962	-	Customer evaluation kit for BFU520, BFU530 and BFU550 [1]	-			

- [1] The customer evaluation kit contains the following:
 - a) Unpopulated RF amplifier Printed-Circuit Board (PCB)
 - b) Unpopulated RF amplifier Printed-Circuit Board (PCB) with emitter degeneration
 - c) Four SMA connectors for fitting unpopulated Printed-Circuit Board (PCB)
 - d) BFU520, BFU530 and BFU550 samples
 - e) USB stick with data sheets, application notes, models, S-parameter and noise files

4. Marking

Table 4. Marking

Type number	Marking	Description
BFU520	*TA	* = t : made in Malaysia
		* = w : made in China

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5. Design support

Table 5. Available design support

Download from the BFU520 product information page on http://www.nxp.com.

Support item	Available	Remarks
Device models for Agilent EEsof EDA ADS	yes	Based on Mextram device model.
SPICE model	yes	Based on Gummel-Poon device model.
S-parameters	yes	
Noise parameters	yes	
Customer evaluation kit	yes	See Section 3 and Section 10.
Solder pattern	yes	
Application notes	yes	See Section 10.1 and Section 10.2.

6. Limiting values

Table 6. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CB}	collector-base voltage	open emitter	-	30	V
V _{CE}	collector-emitter voltage	open base	-	16	V
		shorted base	-	30	V
V _{EB}	emitter-base voltage	open collector	-	3	V
I _C	collector current		-	50	mA
T _{stg}	storage temperature		-65	+150	°C
V _{ESD}	electrostatic discharge voltage	Human Body Model (HBM) According to JEDEC standard 22-A114E	-	±150	V
		Charged Device Model (CDM) According to JEDEC standard 22-C101B	-	±2	kV

7. Recommended operating conditions

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{CB}	collector-base voltage	open emitter	-	-	24	V
V_{CE}	collector-emitter voltage	open base	-	-	12	V
		shorted base	-	-	24	V
V_{EB}	emitter-base voltage	open collector	-	-	2	V
I _C	collector current		-	-	30	mA
Pi	input power	$Z_S = 50 \Omega$	-	-	10	dBm
Tj	junction temperature		-40	-	+150	°C
P _{tot}	total power dissipation	$T_{sp} \le 87 ^{\circ}C$ [1]	-	-	450	mW

^[1] T_{sp} is the temperature at the solder point of the collector lead.

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Thermal characteristics

Table 8. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point	<u>[1]</u>	140	K/W

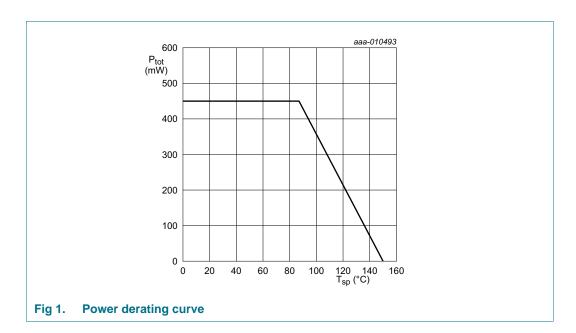
[1] T_{sp} is the temperature at the solder point of the collector lead.

 T_{sp} has the following relation to the ambient temperature T_{amb} :

 $T_{sp} = T_{amb} + P \times R_{th(sp-a)}$

With P being the power dissipation and R_{th(sp-a)} being the thermal resistance between the solder point and ambient. $R_{th(sp-a)}$ is determined by the heat transfer properties in the application.

The heat transfer properties are set by the application board materials, the board layout and the environment e.g. housing.



Characteristics

Characteristics

T_{amb} = 25 °C unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)CBO}$	collector-base breakdown voltage	$I_C = 100 \text{ nA}; I_E = 0 \text{ mA}$	24	-	-	V
$V_{(BR)CEO}$	collector-emitter breakdown voltage	I _C = 150 nA; I _B = 0 mA	12	-	-	V
I _C	collector current		-	5	30	mA
I _{CBO}	collector-base cut-off current	I _E = 0 mA; V _{CB} = 8 V	-	<1	-	nA
h _{FE}	DC current gain	I _C = 5 mA; V _{CE} = 8 V	60	95	200	
Ce	emitter capacitance	V _{EB} = 0.5 V; f = 1 MHz	-	0.74	-	pF
C _{re}	feedback capacitance	V _{CE} = 8 V; f = 1 MHz	-	0.28	-	pF
C _c	collector capacitance	V _{CB} = 8 V; f = 1 MHz	-	0.52	-	pF
f⊤	transition frequency	$I_C = 10 \text{ mA}; V_{CE} = 8 \text{ V}; f = 900 \text{ MHz}$	-	10.5	-	GHz

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 Table 9.
 Characteristics ...continued

T_{amb} = 25 °C unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
G _{p(max)}	maximum power gain	f = 433 MHz; V _{CE} = 8 V				
		I _C = 1 mA	-	17	-	dB
		I _C = 5 mA	-	23.5	-	dB
		I _C = 10 mA	-	26	-	dB
		f = 900 MHz; V _{CE} = 8 V				
		I _C = 1 mA	-	14	-	dB
		I _C = 5 mA	-	20	-	dB
		I _C = 10 mA	-	22	-	dB
		f = 1800 MHz; V _{CE} = 8 V				
		I _C = 1 mA	-	11.5	-	dB
		I _C = 5 mA	-	17	-	dB
		I _C = 10 mA	-	17.5	-	dB
s ₂₁ ²	insertion power gain	f = 433 MHz; V _{CE} = 8 V				
		I _C = 1 mA	-	10.5	-	dB
		I _C = 5 mA	-	21	-	dB
		I _C = 10 mA	-	23.5	-	dB
		f = 900 MHz; V _{CE} = 8 V				
		I _C = 1 mA	-	9.5	-	dB
		I _C = 5 mA	-	17.5	-	dB
		I _C = 10 mA	-	18.5	-	dB
		f = 1800 MHz; V _{CE} = 8 V				
		I _C = 1 mA	-	6.5	-	dB
		I _C = 5 mA	-	12	-	dB
		I _C = 10 mA	-	13	-	dB
NF _{min}	minimum noise figure	f = 433 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}				
		I _C = 1 mA	-	0.55	-	dB
		$I_C = 5 \text{ mA}$	-	0.7	-	dB
		I _C = 10 mA	-	0.9	-	dB
		f = 900 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}				
		I _C = 1 mA	-	0.65	-	dB
		I _C = 5 mA	-	0.8	-	dB
		I _C = 10 mA	-	0.95	-	dB
		f = 1800 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}				
		I _C = 1 mA	-	0.85	-	dB
		I _C = 5 mA	-	0.9	-	dB
				+		

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 Table 9.
 Characteristics ...continued

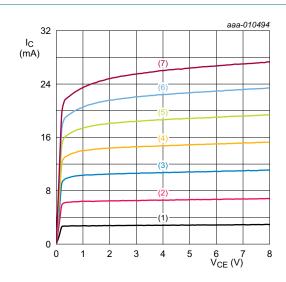
T_{amb} = 25 °C unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
G _{ass}	associated gain	$f = 433 \text{ MHz}; V_{CE} = 8 \text{ V}; \Gamma_{S} = \Gamma_{opt}$				
		I _C = 1 mA	-	26	-	dB
		I _C = 5 mA	-	25.5	-	dB
		I _C = 10 mA	-	26	-	dB
		f = 900 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}				
		I _C = 1 mA	-	18	-	dB
		I _C = 5 mA	-	19	-	dB
		I _C = 10 mA	-	20	-	dB
		f = 1800 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}				
		I _C = 1 mA	-	11.5	-	dB
		I _C = 5 mA	-	13.5	-	dB
		I _C = 10 mA	-	14	-	dB
P _{L(1dB)}	output power at 1 dB gain compression	$f = 433$ MHz; $V_{CE} = 8$ V; $Z_{S} = Z_{L} = 50$ Ω				
		I _C = 5 mA	-	1	-	dBm
		I _C = 10 mA	-	5.5	-	dBm
		$f = 900 \text{ MHz}$; $V_{CE} = 8 \text{ V}$; $Z_{S} = Z_{L} = 50 \Omega$				
		I _C = 5 mA	-	2	-	dBm
		I _C = 10 mA	-	6.5	-	dBm
		$f = 1800 \text{ MHz}; V_{CE} = 8 \text{ V}; Z_{S} = Z_{L} = 50 \Omega$				
		I _C = 5 mA	-	2	-	dBm
		I _C = 10 mA	-	7	-	dBm
IP3 _o	output third-order intercept point	f_1 = 433 MHz; f_2 = 434 MHz; V_{CE} = 8 V; Z_S = Z_L = 50 Ω				
		I _C = 5 mA	-	10.5	-	dBm
		I _C = 10 mA	-	15	-	dBm
		f_1 = 900 MHz; f_2 = 901 MHz; V_{CE} = 8 V; Z_S = Z_L = 50 Ω				
		I _C = 5 mA	-	11.5	-	dBm
		I _C = 10 mA	-	16	-	dBm
		f_1 = 1800 MHz; f_2 = 1801 MHz; V_{CE} = 8 V; Z_S = Z_L = 50 Ω				
		I _C = 5 mA	-	11.5	-	dBm
		I _C = 10 mA	-	16.5	-	dBm
	1	<u> </u>	1	1	1	

^[1] If K > 1 then $G_{p(max)}$ is the maximum power gain. If K < 1 then $G_{p(max)} = MSG$.

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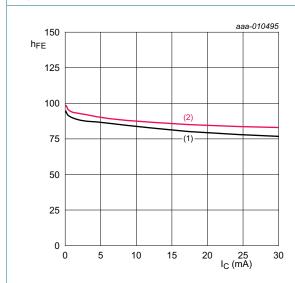
9.1 Graphs



 $T_{amb} = 25 \, ^{\circ}C.$

- (1) $I_B = 25 \mu A$
- (2) $I_B = 75 \mu A$
- (3) $I_B = 125 \mu A$
- (4) $I_B = 175 \mu A$
- (5) $I_B = 225 \mu A$
- (6) $I_B = 275 \mu A$
- (7) $I_B = 325 \mu A$

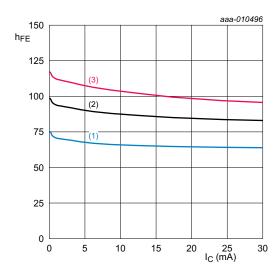
Fig 2. Collector current as a function of collector-emitter voltage; typical values



 $T_{amb} = 25 \, ^{\circ}C.$

- (1) $V_{CE} = 3.0 \text{ V}$
- (2) $V_{CE} = 8.0 \text{ V}$

Fig 3. DC current gain as function of collector current; typical values



 $V_{CE} = 8 \text{ V}.$

- (1) $T_{amb} = -40 \, ^{\circ}C$
- (2) $T_{amb} = +25 \, ^{\circ}C$
- (3) $T_{amb} = +125 \, ^{\circ}C$

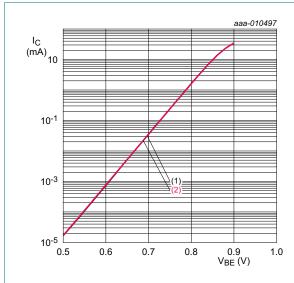
Fig 4. DC current gain as function of collector current; typical values

BFU520

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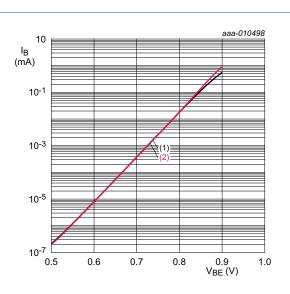
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 $T_{amb} = 25 \, ^{\circ}C.$

- (1) $V_{CE} = 3.0 \text{ V}$
- (2) $V_{CE} = 8.0 \text{ V}$

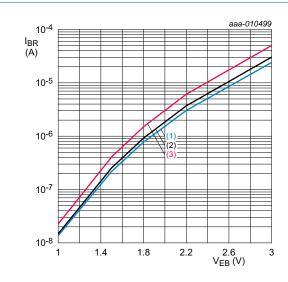
Fig 5. Collector current as a function of base-emitter voltage; typical values



 $T_{amb} = 25 \, ^{\circ}C.$

- (1) $V_{CE} = 3.0 \text{ V}$
- (2) $V_{CE} = 8.0 \text{ V}$

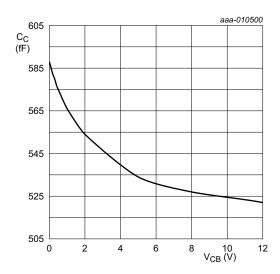
Fig 6. Base current as a function of base-emitter voltage; typical values



 $V_{CE} = 3 \text{ V}.$

- (1) $T_{amb} = -40 \, ^{\circ}C$
- (2) $T_{amb} = +25 \, ^{\circ}C$
- (3) $T_{amb} = +125 \, ^{\circ}C$

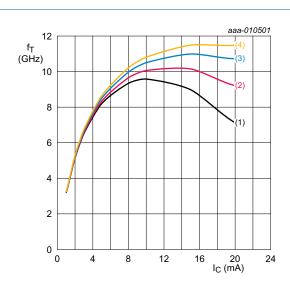
Fig 7. Reverse base current as a function of emitter-base voltage; typical values



 $I_C = 0$ mA; f = 1 MHz; $T_{amb} = 25$ °C.

Fig 8. Collector capacitance as a function of collector-base voltage; typical values

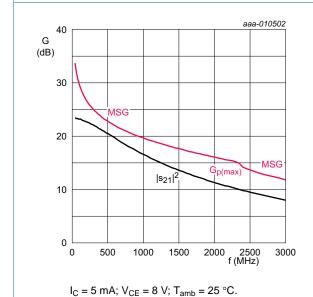
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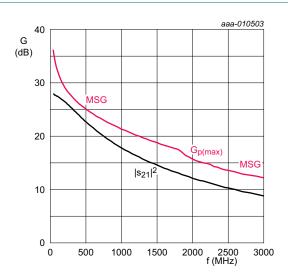
 $T_{amb} = 25 \, ^{\circ}C.$

- (1) $V_{CE} = 3.3 \text{ V}$
- (2) $V_{CE} = 5.0 \text{ V}$
- (3) $V_{CE} = 8.0 \text{ V}$
- (4) $V_{CE} = 12.0 \text{ V}$

Fig 9. Transition frequency as a function of collector current; typical values



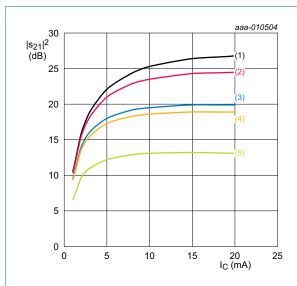




 I_C = 10 mA; V_{CE} = 8 V; T_{amb} = 25 °C.

Fig 11. Gain as a function of frequency; typical values

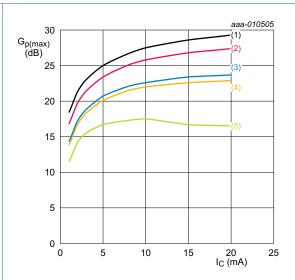
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 V_{CE} = 8 V; T_{amb} = 25 °C.

- (1) f = 300 MHz
- (2) f = 433 MHz
- (3) f = 800 MHz
- (4) f = 900 MHz
- (5) f = 1800 MHz





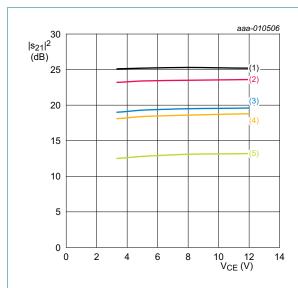
 V_{CE} = 8 V; T_{amb} = 25 °C.

If K >1 then $G_{p(max)}$ = maximum power gain. If K < 1 then $G_{p(max)}$ = MSG.

- (1) f = 300 MHz
- (2) f = 433 MHz
- (3) f = 800 MHz
- (4) f = 900 MHz
- (5) f = 1800 MHz

Fig 13. Maximum power gain as a function of collector current; typical values

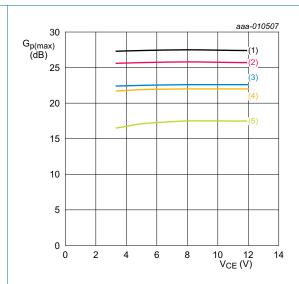
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 I_C = 10 mA; T_{amb} = 25 °C.

- (1) f = 300 MHz
- (2) f = 433 MHz
- (3) f = 800 MHz
- (4) f = 900 MHz
- (5) f = 1800 MHz

Fig 14. Insertion power gain as a function of collector-emitter voltage; typical values



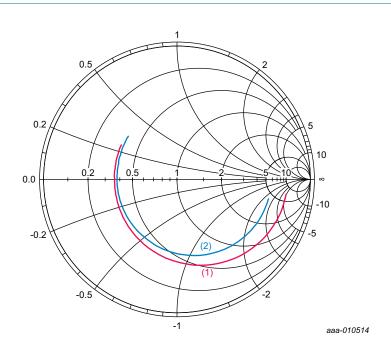
 I_C = 10 mA; T_{amb} = 25 °C.

If K >1 then $G_{p(max)}$ = maximum power gain. If K < 1 then $G_{p(max)}$ = MSG.

- (1) f = 300 MHz
- (2) f = 433 MHz
- (3) f = 800 MHz
- (4) f = 900 MHz
- (5) f = 1800 MHz

Fig 15. Maximum power gain as a function of collector-emitter voltage; typical values

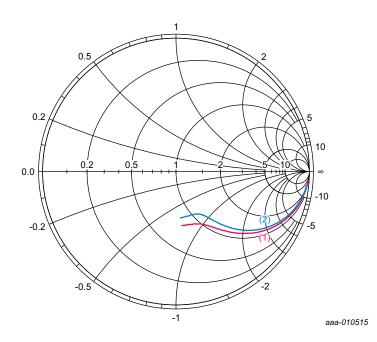
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 V_{CE} = 8 V; 40 MHz \leq f \leq 3 GHz.

- (1) $I_C = 5 \text{ mA}$
- (2) $I_C = 10 \text{ mA}$

Fig 16. Input reflection coefficient (s₁₁); typical values

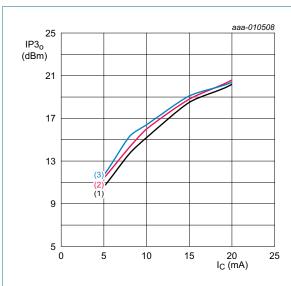


 V_{CE} = 8 V; 40 MHz \leq f \leq 3 GHz.

- (1) $I_C = 5 \text{ mA}$
- (2) $I_C = 10 \text{ mA}$

Fig 17. Output reflection coefficient (s_{22}) ; typical values

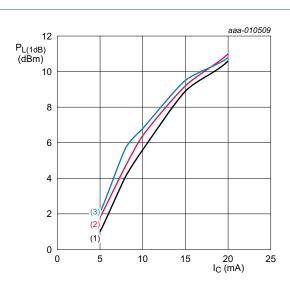
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 $V_{CE} = 8 \text{ V}; T_{amb} = 25 \,^{\circ}\text{C}.$

- (1) $f_1 = 433 \text{ MHz}$; $f_2 = 434 \text{ MHz}$
- (2) $f_1 = 900 \text{ MHz}$; $f_2 = 901 \text{ MHz}$
- (3) $f_1 = 1800 \text{ MHz}$; $f_2 = 1801 \text{ MHz}$

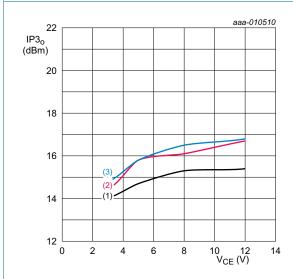
Fig 18. Output third-order intercept point as a function of collector current; typical values



 $V_{CE} = 8 \text{ V}; T_{amb} = 25 \,^{\circ}\text{C}.$

- (1) f = 433 MHz
- (2) f = 900 MHz
- (3) f = 1800 MHz

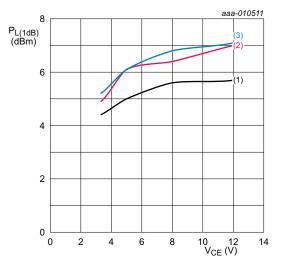
Fig 19. Output power at 1 dB gain compression as a function of collector current; typical values



 $I_C = 10 \text{ mA}; T_{amb} = 25 \, ^{\circ}\text{C}.$

- (1) $f_1 = 433 \text{ MHz}$; $f_2 = 434 \text{ MHz}$
- (2) $f_1 = 900 \text{ MHz}$; $f_2 = 901 \text{ MHz}$
- (3) $f_1 = 1800 \text{ MHz}$; $f_2 = 1801 \text{ MHz}$

Fig 20. Output third-order intercept point as a function of collector-emitter voltage; typical values

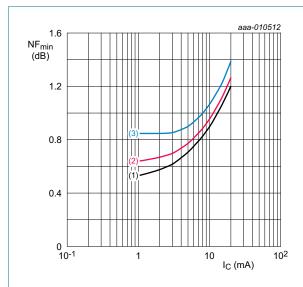


 $I_C = 10 \text{ mA}; T_{amb} = 25 \, ^{\circ}\text{C}.$

- (1) f = 433 MHz
- (2) f = 900 MHz
- (3) f = 1800 MHz

Fig 21. Output power at 1 dB gain compression as a function of collector-emitter voltage; typical values

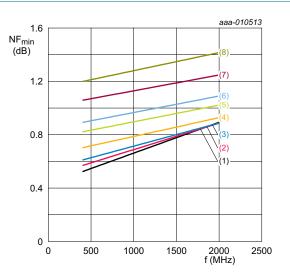
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$$V_{CE}$$
 = 8 V; T_{amb} = 25 °C; Γ_{S} = Γ_{opt} .

- (1) f = 433 MHz
- (2) f = 900 MHz
- (3) f = 1800 MHz

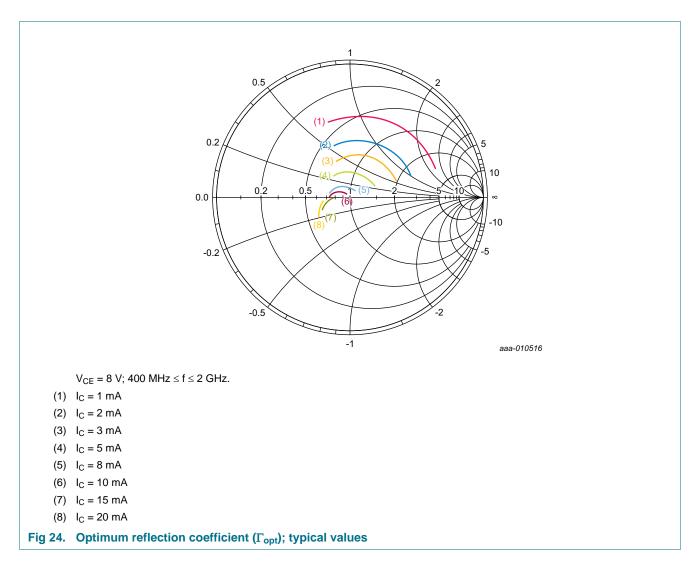
Fig 22. Minimum noise figure as a function of collector current; typical values



$$V_{CE} = 8 \text{ V}; T_{amb} = 25 \text{ °C}; \Gamma_{S} = \Gamma_{opt}.$$

- (1) $I_C = 1 \text{ mA}$
- (2) $I_C = 2 \text{ mA}$
- (3) $I_C = 3 \text{ mA}$
- (4) $I_C = 5 \text{ mA}$
- (5) $I_C = 8 \text{ mA}$
- (6) $I_C = 10 \text{ mA}$ (7) $I_C = 15 \text{ mA}$
- (8) $I_C = 20 \text{ mA}$
- Fig 23. Minimum noise figure as a function of frequency; typical values

NPN wideband silicon RF transistor



10. Application information

More information about the following application example can be found in the application notes. See Section 5 "Design support".

The following application example can be implemented using the evaluation kit. See Section 3 "Ordering information" for the order type number.

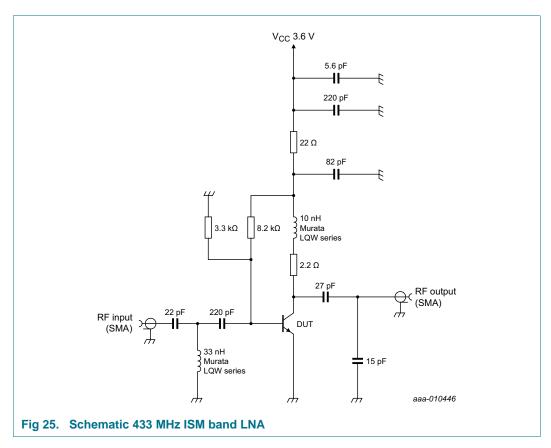
The following application example can be simulated using the simulation package. See Section 5 "Design support".

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10.1 Application example: 433 ISM band LNA

433 ISM band LNA, optimized for low noise.

More detailed information of the application example can be found in the application note: *AN11427*.



Remark: fine tuning of components maybe required depending on PCB parasitics.

Table 10. Application performance data at 433 MHz

 $I_{CC} = 7 \text{ mA}; V_{CC} = 3.6 \text{ V}$

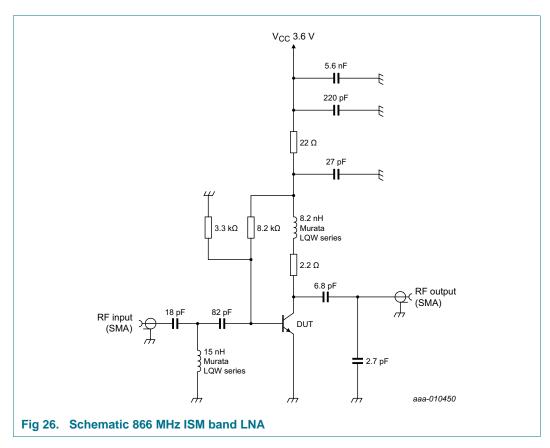
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$ s_{21} ^2$	insertion power gain		-	19	-	dB
NF	noise figure		-	1.0	-	dB
IP3 _o	output third-order intercept point	$f_1 = 433.1 \text{ MHz}; f_2 = 433.2 \text{ MHz};$ $P_i = -30 \text{ dBm per carrier}$	-	11	-	dBm

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10.2 Application example: 866 ISM band LNA

866 ISM band LNA, optimized for low noise.

More detailed information of the application example can be found in the application note: *AN11428*.



Remark: fine tuning of components maybe required depending on PCB parasitics.

Table 11. Application performance data at 866 MHz

 $I_{CC} = 7 \text{ mA}; V_{CC} = 3.6 \text{ V}$

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$ s_{21} ^2$	insertion power gain		-	16	-	dB
NF	noise figure		-	1.1	-	dB
IP3 _o		$f_1 = 866.1 \text{ MHz}; f_2 = 866.2 \text{ MHz};$ $P_i = -30 \text{ dBm per carrier}$	-	14	-	dBm

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11. Package outline

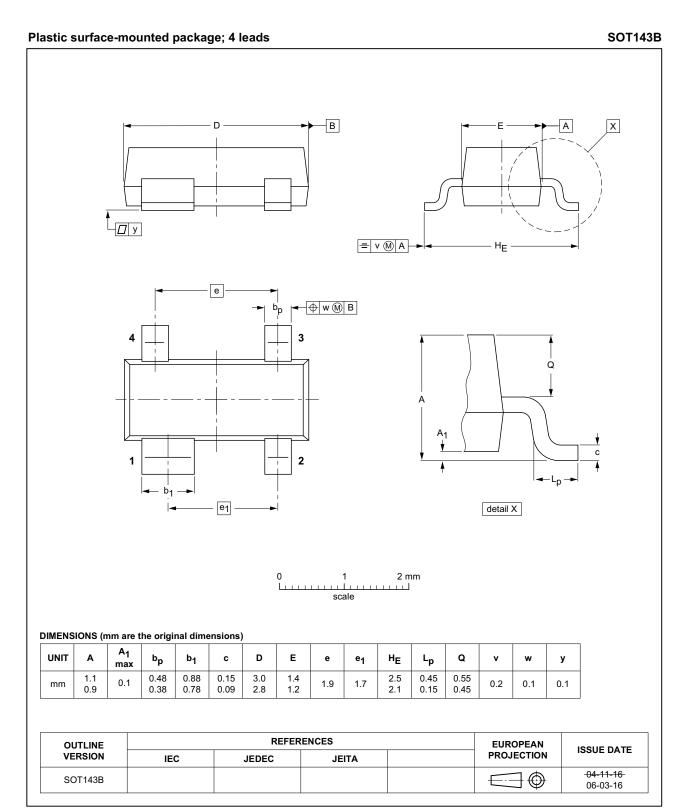


Fig 27. Package outline SOT143B

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12. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

13. Abbreviations

Table 12. Abbreviations

Acronym	Description
AEC	Automotive Electronics Council
ISM	Industrial, Scientific and Medical
LNA	Low-Noise Amplifier
MSG	Maximum Stable Gain
NPN	Negative-Positive-Negative
SMA	SubMiniature version A

14. Revision history

Table 13. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BFU520 v.2	20140305	Product data sheet	-	BFU520 v.1
Modifications:	 <u>Section 10.1 on page 16</u>: a remarks has been added below <u>Figure 25</u>. <u>Section 10.2 on page 17</u>: a remarks has been added below <u>Figure 26</u>. 			
BFU520 v.1	20140220	Product data sheet	-	-

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15. Legal information

15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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